Searcn Notes			

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/790,296	PHAN ET AL.	
Examiner	Art Unit	
Paul Dinh	2825	•

SEARCHED			
Class	Subclass	Date	Examiner
716	19-21	6/1/2005	PD
382	145	6/1/2005	PD
438	14, 16	6/1/2005	PD
430	5, 22, 30	6/1/2005	PD
356	401	7/16/2005	PD
above	update	9/7/2005	PD
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INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
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SEARCH NOT (INCLUDING SEARCH	TES STRATEGY	)
	DATE	EXMR
EAST, IEEE	6/1/2005	PD